Application/Control No. Applicant(s)/Patent Under Reexamination 10/706,397 BETARBET, SANDEEP Notice of References Cited Examiner **Art Unit** Page 1 of 1 Greg Bengzon 2144 **U.S. PATENT DOCUMENTS Document Number** Date Name Country Code-Number-Kind Code Classification MM-YYYY US-7,065,547 B2 06-2006 Persels et al. Α 709/200 * US-2004/0153451 A1 08-2004 Phillips et al. В 707/008 * US-2004/0199514 A1 10-2004 Rosenblatt et al. С 707/010 US-2004/0203636 A1 10-2004 Chan et al. D 455/414.1 * US-2004/0088348 A1 05-2004 Yeager et al. Ε 709/202 * F US-5,944,783 A 08-1999 Nieten, Joseph Lee 709/202 * US-7,254,608 B2 08-2007 G Yeager et al. 709/203 * US-2002/0147774 A1 10-2002 Н Lisiecki et al. 709/203 * 02-2004 US-2004/0039781 A1 1 LaVallee et al. 709/205 * US-2002/0143888 A1 10-2002 Lisiecki et al. 709/214 * US-2003/0014530 A1 01-2003 Κ Bodin et al. 709/231 US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Country Code-Number-Kind Code MM-YYYY Classification Ν 0 Ρ Q R S T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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